10/516268 DT05 Recid PCT/PTO 0 9 DEC 2014

Form PTO 1449 U.S. DEPARTMI (Modified) PATENT AND 1			OF COMMERCE DEMARK OFFICE	ATTY DOCKET NO. 262637US3X PCT		SERIAL NO.10/516, 298 New U.S. PCT Application			
					Based on PCT/JP03/07445				
			20110445	APPLICANT					
LIST OF	KEFE	RENCES CITED BY AF	PLICANT	Kentaro YAMAUCHI, et al.					
				FILING DATE		GROUP 3746			
				Herewith		·			
U.S. PATENT DOCUMENTS									
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS			
7PH/	A	5 567 125	10/22/96	NOAH, Bruce C. et al.	<u> </u>				
/PH/	AB	4 575 314	03/11/86	TEUBLER, Heinz et al.	<u> </u>				
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	AM			:					
	AN								
			FO	REIGN PATENT DOCUMENTS					
		DOCUMENT	<u> </u>		TRANSLATION				
		DOCUMENT NUMBER	DATE	COUNTRY		YES NO			
/PH/	AO	11-63270	03/05/99	JP (with English abstract)				NO	
/PH/	AP	184388/1984	12/07/84	JP				NO	
/PH/	AQ	96/13665	05/09/96	VO (with English abstract & equivalent of US 800135)				NO	
/PH/	AR	90990/1987	06/10/87	JP				NO	
7PH/	AS	2-139386	11/21/90	JP				NO	
	AT								
	AU								
	AV			·					
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)									
	AW								
	AX								
	AY	i							
	AZ	Additional References sheet(s) attached							
Examiner	/Pa	Patrick Hamo/				Date Considered 03/15/2007			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.									